



# NSF International Strategic Registrations

789 North Dixboro Road, Ann Arbor, Michigan 48105  
(888) NSF-9000

## Certificate of Registration

This certifies that the Quality Management System of  
**Method Electronics, Inc.**

111 W. Buchanan St.  
Carthage, Illinois, 62321 USA

has been assessed by NSF-ISR and found to be in conformance to the following standard(s):

### ISO/TS 16949:2002

*Having been audited in accordance with the "Rules for the registration scheme for ISO/TS 16949:2002 2nd Edition"*

#### Scope of Registration:

Design, manufacture and assembly of electrical/mechanical devices.

**Exclusions:** None

[Supplier Code(s): Ford- M363C / GM- 122579824 / DaimlerChrysler- 23199B / Visteon - M363C]

#### Industrial Classification:

IAF: 19  
SIC: 3625  
NACE: DL 31.1

IATF Certificate Number: 0064961  
Certificate Number: 4Y311-TS4  
Certificate Issue Date: 13-Mar-2008  
Company Initial Date: 31-Aug-1995  
Registration Date: 29-Feb-2008  
Expiration Date\*: 28-Feb-2011

*Christian B. Lupo*  
**Christian B. Lupo, General Manager**  
NSF-ISR, Ltd.

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Authorized Registration and/or Accreditation Marks

This certificate is the property of NSF-ISR and must be returned upon request. \*Company is audited for compliance at regular intervals. To verify registration call (888) NSF-9000 or visit our web site at [www.nsf-isr.org](http://www.nsf-isr.org).



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ANNEX PAGE FOR CERTIFICATE REGISTRATION NUMBER:

4Y311-TS4

IATF CERTIFICATE NUMBER: 0064961

CERTIFICATE ISSUE DATE: 13-Mar-2008

CERTIFICATE EXPIRATION DATE: 28-Feb-2011

Methode Electronics, Inc.

111 W. Buchanan St.

Carthage, Illinois, 62321 USA

<b>Remote Location:</b> Methode Electronics, Inc. 3801 W. Military Highway McAllen, TX, 78503 US	<b>Scope:</b> Warehouse and shipping.
<b>Remote Location:</b> Methode Electronics, Inc. 24585 Evergreen Rd. Southfield, MI, 48075 US	<b>Scope:</b> Design of electrical/mechanical devices.

This annex is only valid in connection with the above-mentioned certificate issued by NSF-ISR